

Ion Beam Analysis (IBA) Applications

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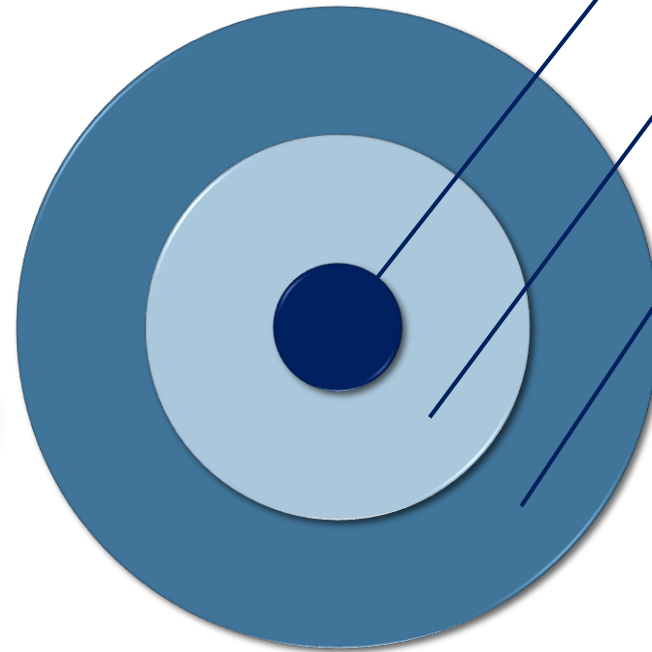
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I am going to talk about...

Why am I speaking about the application of ions?

Steps during investigations.

Results and conclusion.



*A simple low-energy accelerator set up
 *research, education, study of medical radioisotopes production.

Energies: Up to about **10 keV/u** (phase I)

Expansion with RFQ (phase II)
 final energy of- **up to 0.5-5 MeV/u**

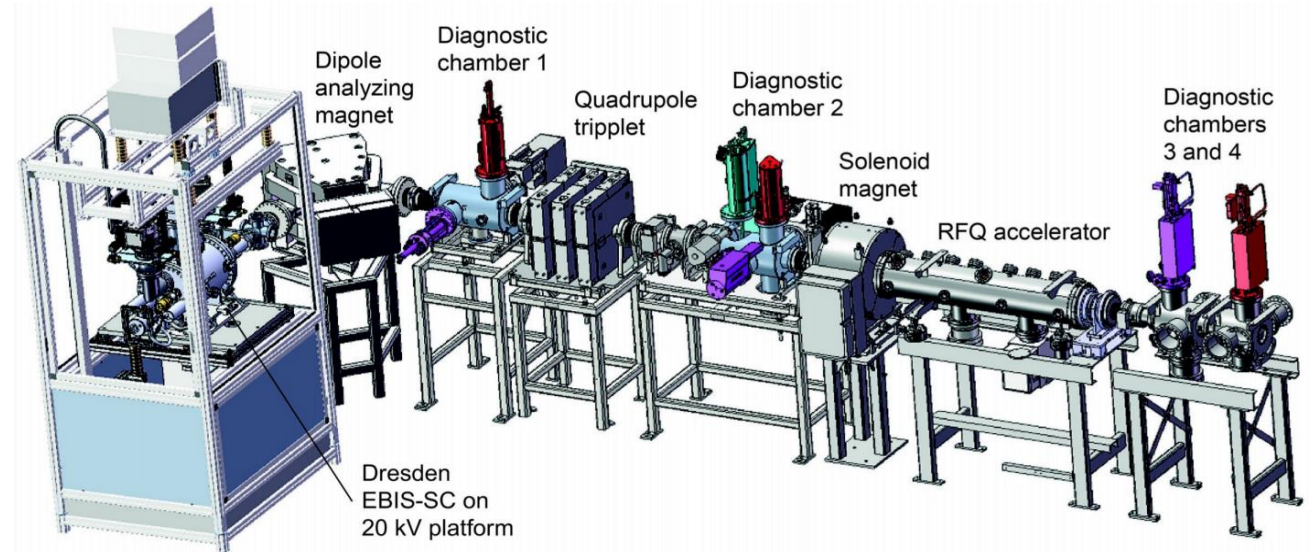
Further studies
 What are the potential applications?
 What is the optimal final energy?

Nanogan source provides ions (Table 1);
 RF power up to 100W; the maximum extracting voltage is 20 kV.

Table 1. Nanogan- an ECR ion source provides:

ion / Q	1	2	4	6	8	9	12	14
H	1000							
He	1000	100						
Ar	300		140	45	20	5		
Xe							10	5
Ta					10		10	5
Au			10	9	8	6		2

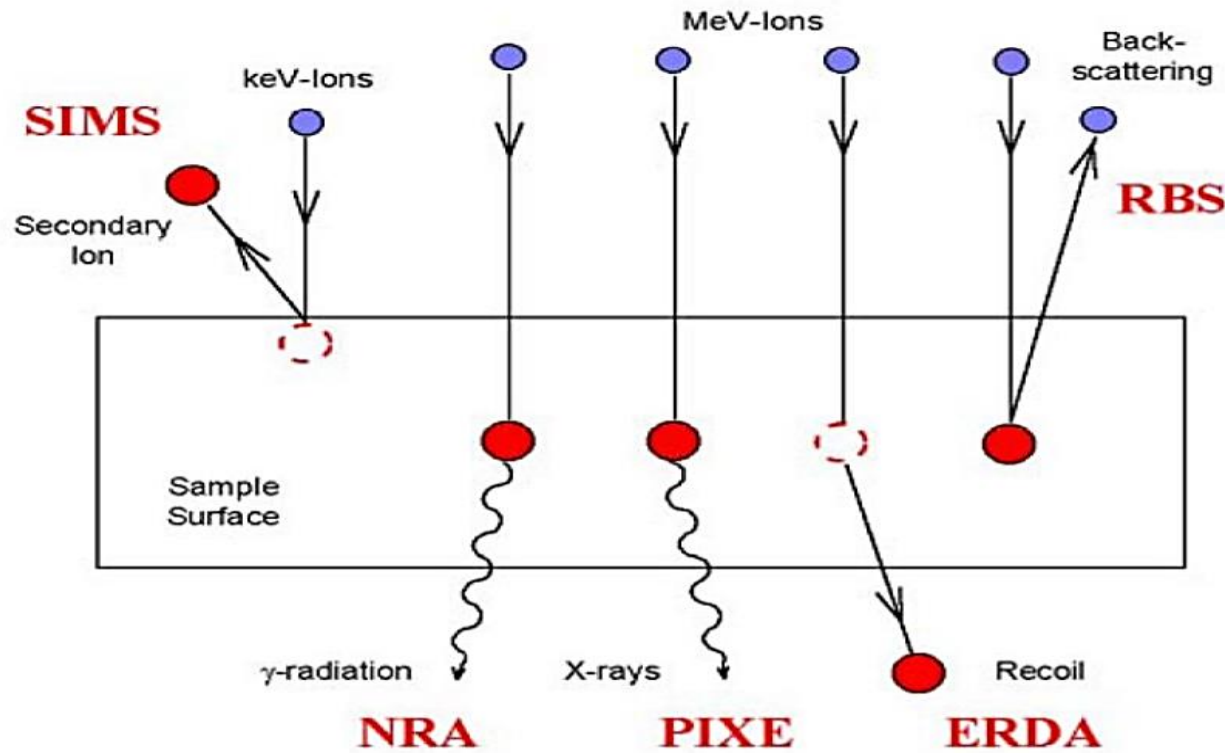
Beam intensity for various charge states given in electric μA



¹RFQ is foreseen for phase 2

Fig. 1. Future test stand

Ion Beam Analysis



Another IBA technique that exists at keV energies- LEIS (Low Energy Ion Scattering) is not shown in the figure 2.

- [1] SIMS- Secondary-Ion Mass Spectrometry
- [2] NRA- Nuclear Reaction Analysis
- [3] PIXE- Particle Induced X- rays Emission
- [4] ERDA- Elastic Recoil Detection Analysis
- [5] EBS- Elastic or Nuclear (non Rutherford) Backscattering Spectrometry
- [6] RBS- Rutherford Backscattering Spectrometry
- [7] LEIS- Low Energy Ion Scattering

Fig. 2. Energies for IBA techniques

Secondary Ion Mass Spectrometry (SIMS)

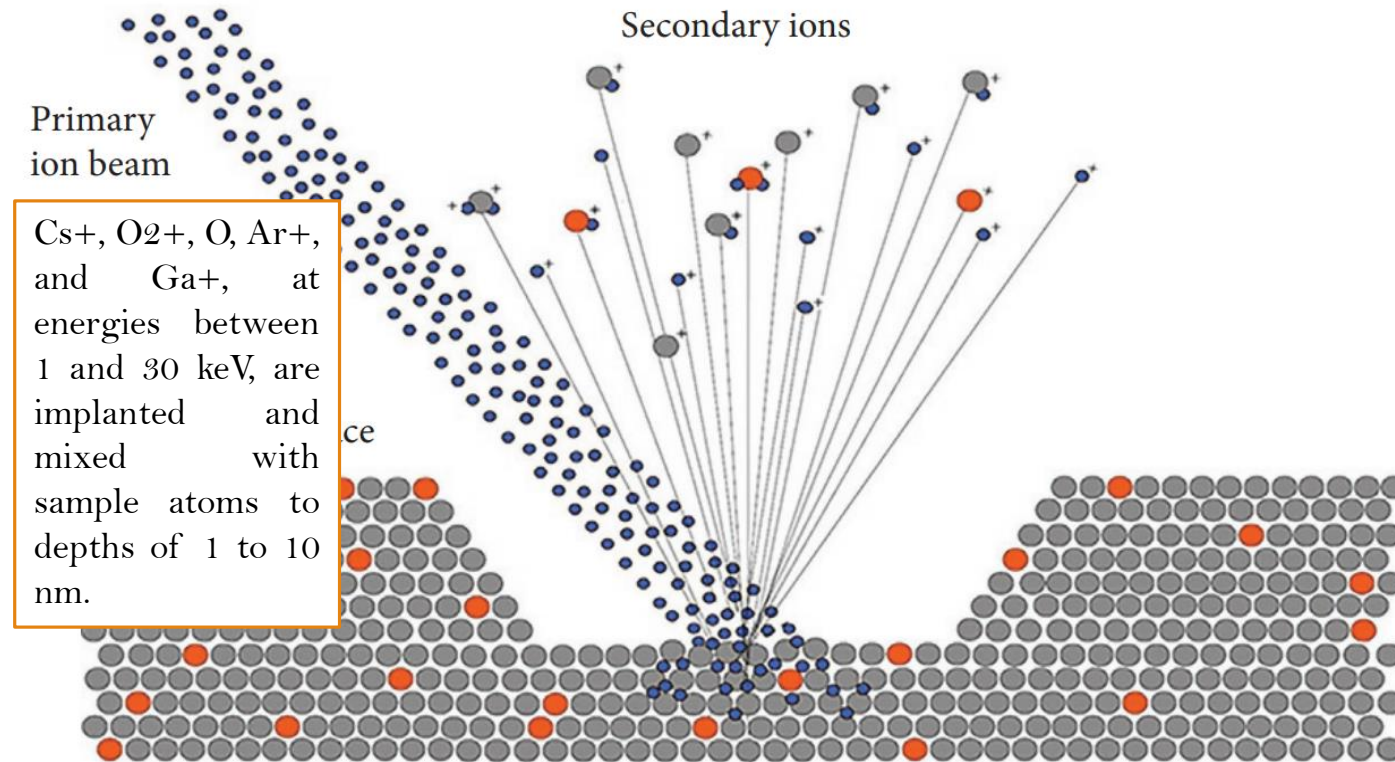
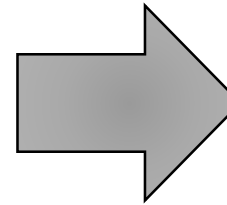


Fig. 3. Schematic illustration showing the SIMS sputtering and ionization process.



Application in Materials Science.
*provides localized elemental, isotopic and molecular characterization of the sample surface.
*insulators, semiconductors, metals and biological samples.

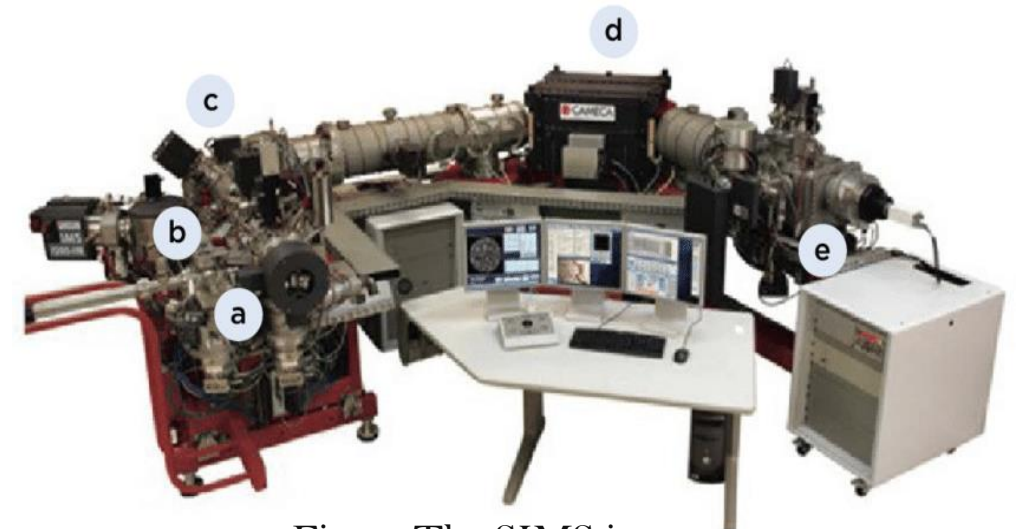


Fig. 4. The SIMS instrument
(a) sample chamber, (b) primary ion source, (c) electrostatic analyser, (d) magnet and (e) detection unit.

Low Energy Ion Scattering (LEIS)

The elemental composition of the outermost atomic layer of a material, and provides depth profile information about its outer ca. 10 nm.

LEIS is useful for studying:

- the relationships between surface chemistry and surface related phenomena such as wetting, adhesion, contamination, and thin film growth.

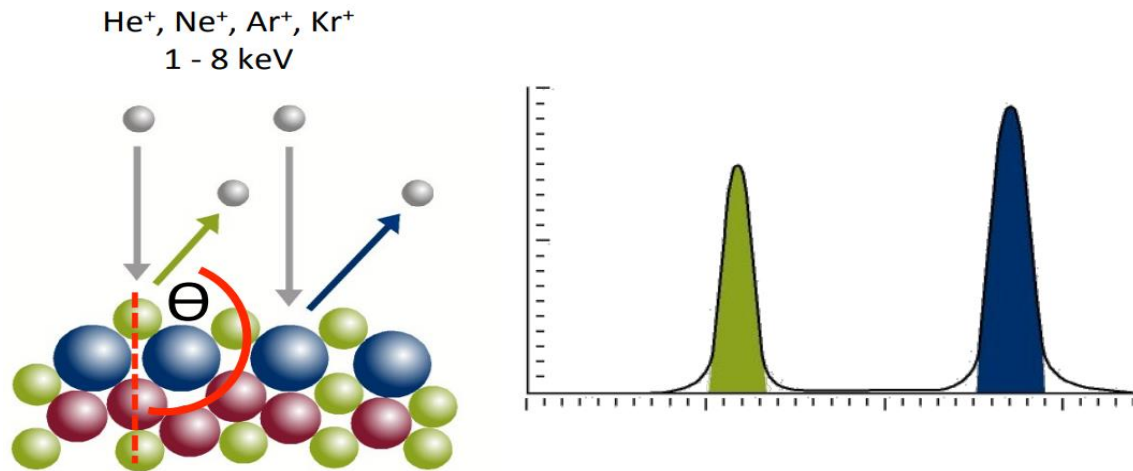


Fig. 5. (Left) Noble gas ion bombardment of a surface with two types of exposed atoms. (Right) LEIS signal corresponding to the surface on the left. Note that there is no LEIS signal from the 'red' atoms.

Method	Ion beam	Beam energy	Beam current
LEIS	He ⁺	8 keV	5.6 nA

Typical ion currents range from **0.1 to 50 nA**.

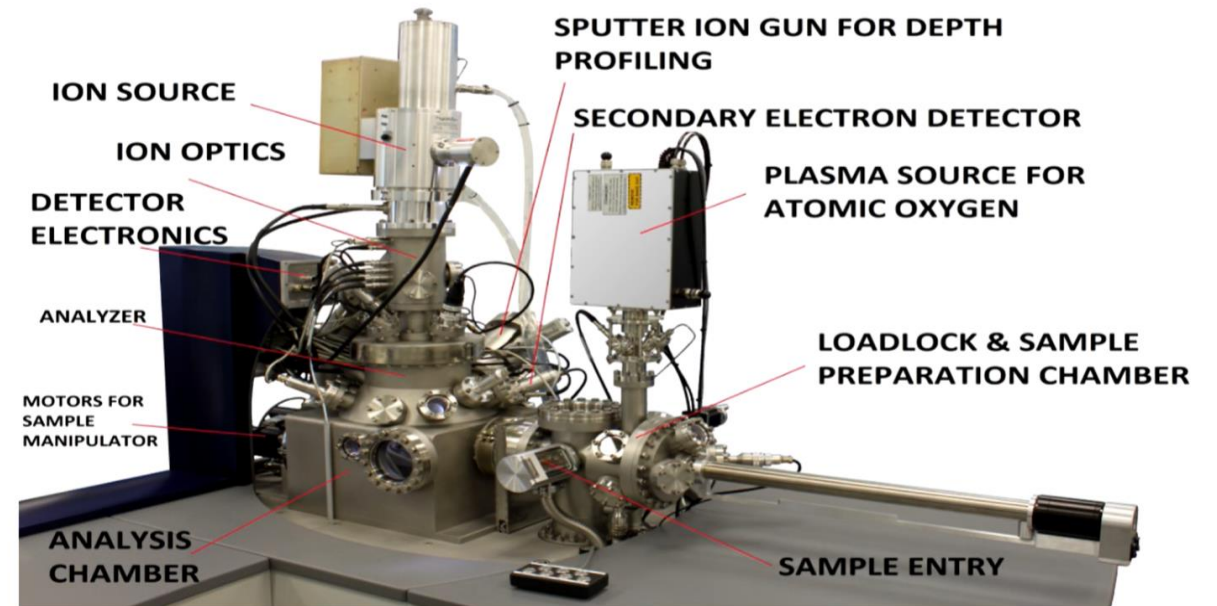
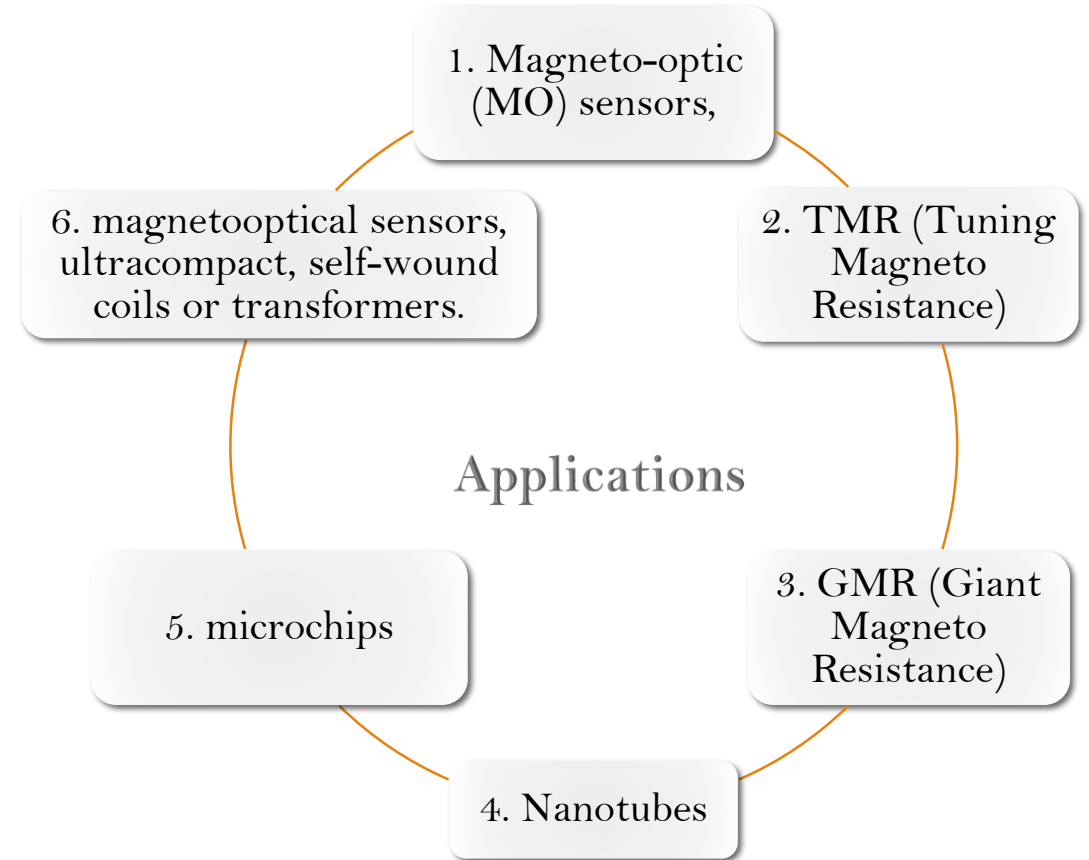
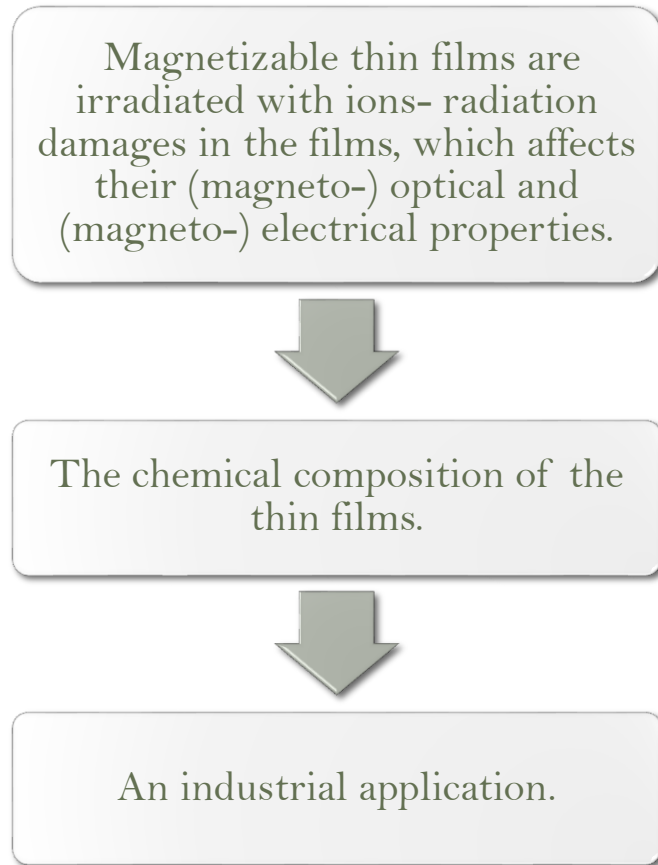


Fig. 6. The real system of components for LEIS

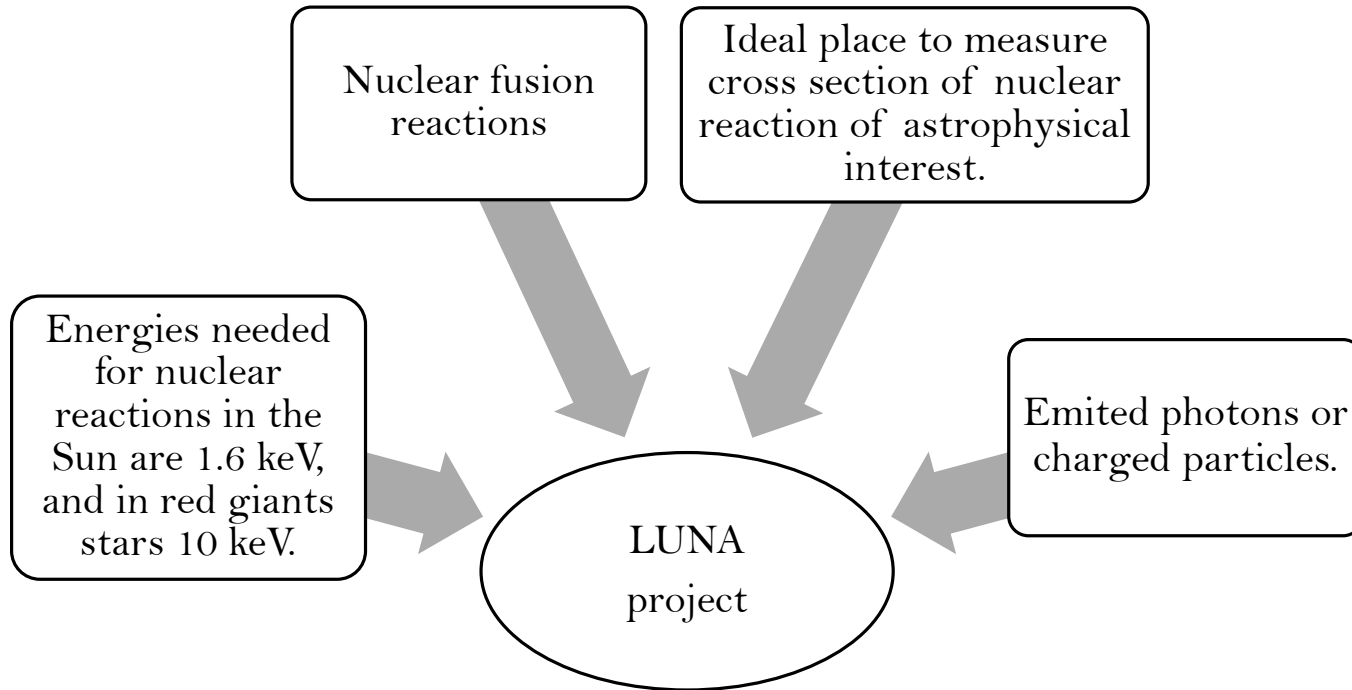


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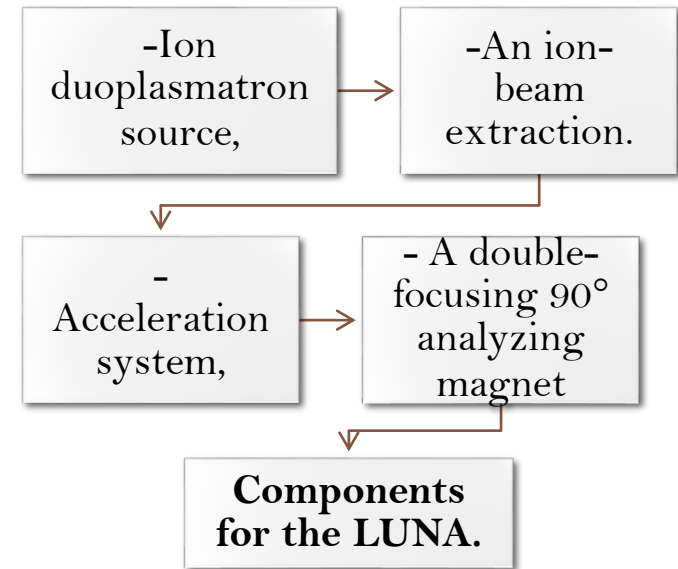
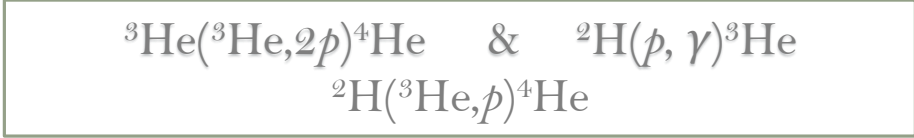
Modification of Magnetizable Multilayer Systems by Ion Implantation



Stellar Physics at keV energies



Ion Source	Ion beams	Current of beams
Radio- frequency	H^+	1 mA
	He^+	(300 – 500) μA



Low Energy Ion Beam Biology Research

Ion Beams of a few tens keVs.

Seeds were bomarded with N ions.

Energy (30-60) keV

Fluences $10^{16} \frac{\text{ions}}{\text{cm}^2}$

For inducing mutation breeding and gene transfer.

- modification of horticultural plants
- a broad spectrum of mutants has been obtained including changes in phenotypes such as the flower color, color intensity, flower shape, petal shape and size

RF- (radiofrequency) driven multicasp plasma source- 30 keV

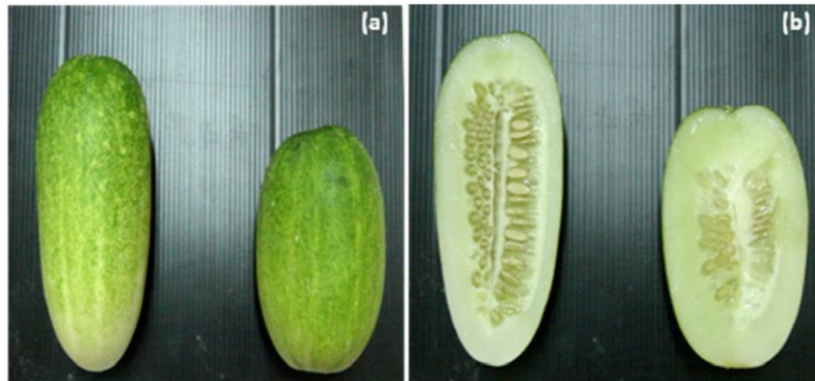


Fig. 11. Effect if ion beam reproductive organ of cucumber
a) and b) control (left) hybrid (right)



Fig. 10. Ion-beam- induced color variation in Gerbera flower petal (original color should be red)_____

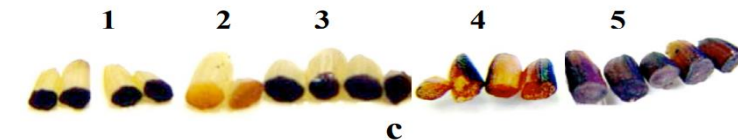
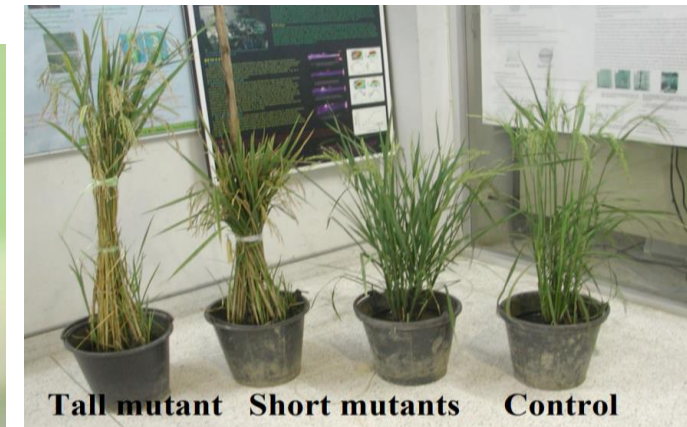


Fig. 8. Ion-beam-induced mutations of purple rice

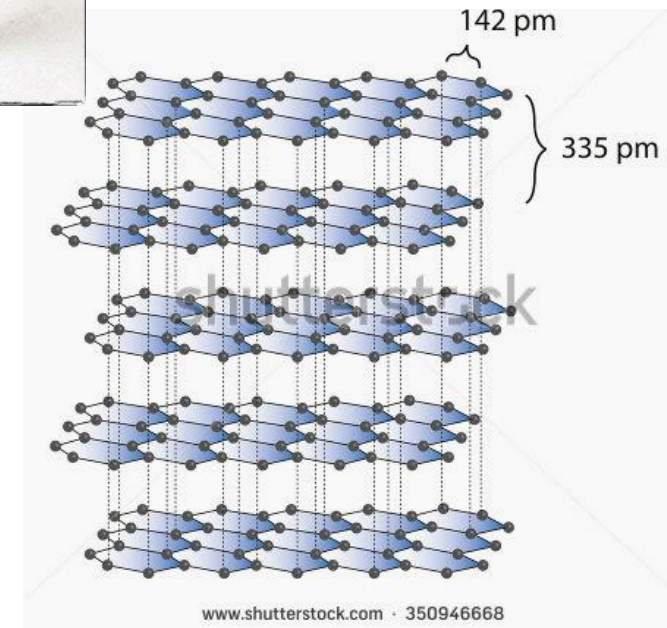
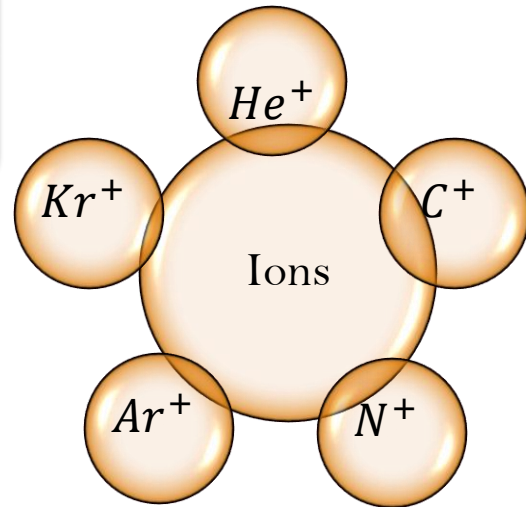


Tall mutant Short mutants Control

Fig. 9. Ion- beam induced mutants showing the straw stem height change

Application of ions on graphene nanomaterials

Bombarding graphene materials with accelerated ions controls the types and number of structural defects.



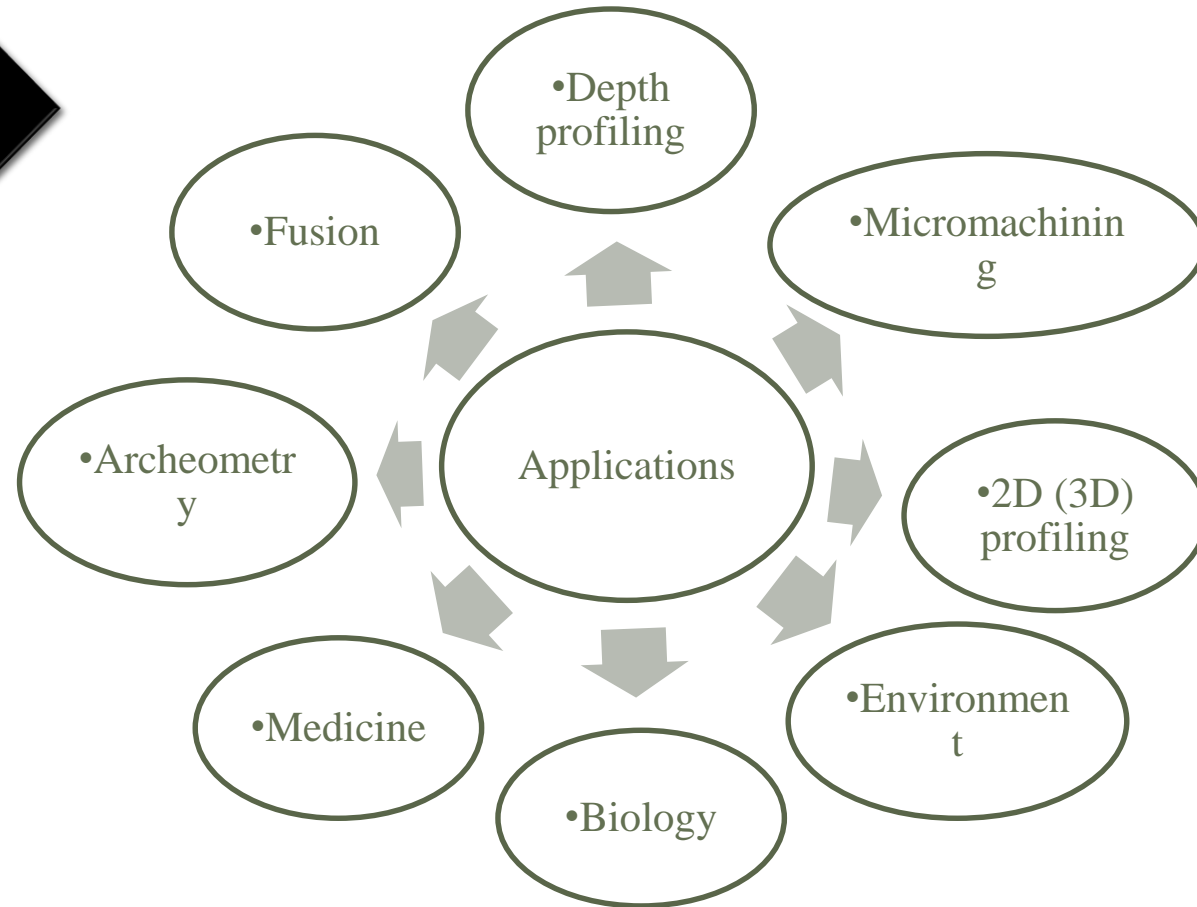
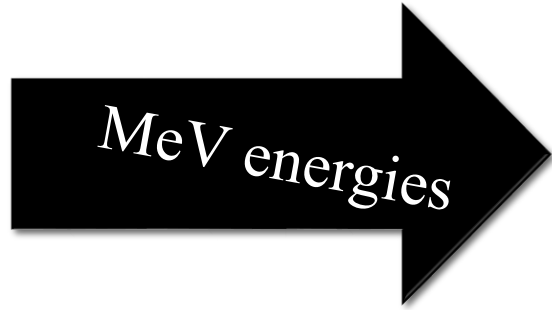
Energy ↑

from 50 eVs
to a few
hundred keVs.

The possibility of controlling the types and number of vacancies by choosing a corresponding ion type and its velocity.

Research and practical application of these systems.

RFQ provides...



Particle Induced X-rays Emission- PIXE

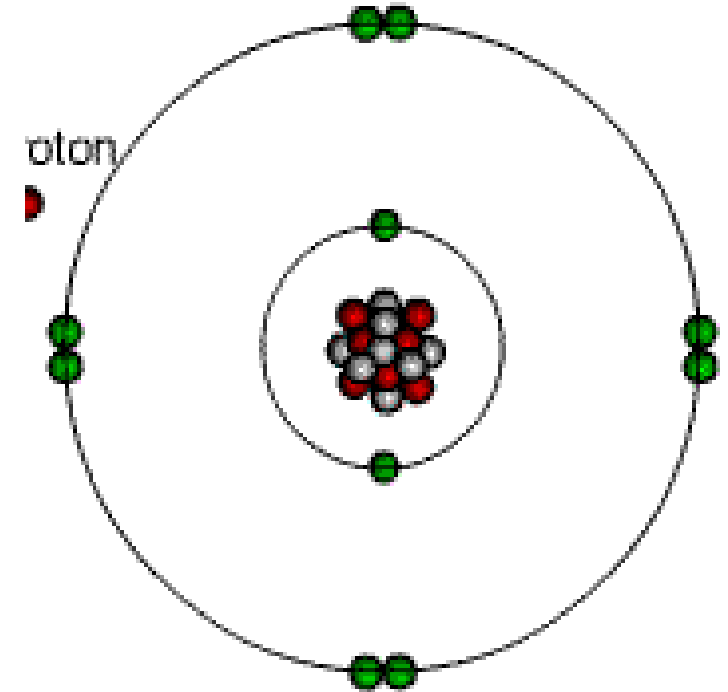
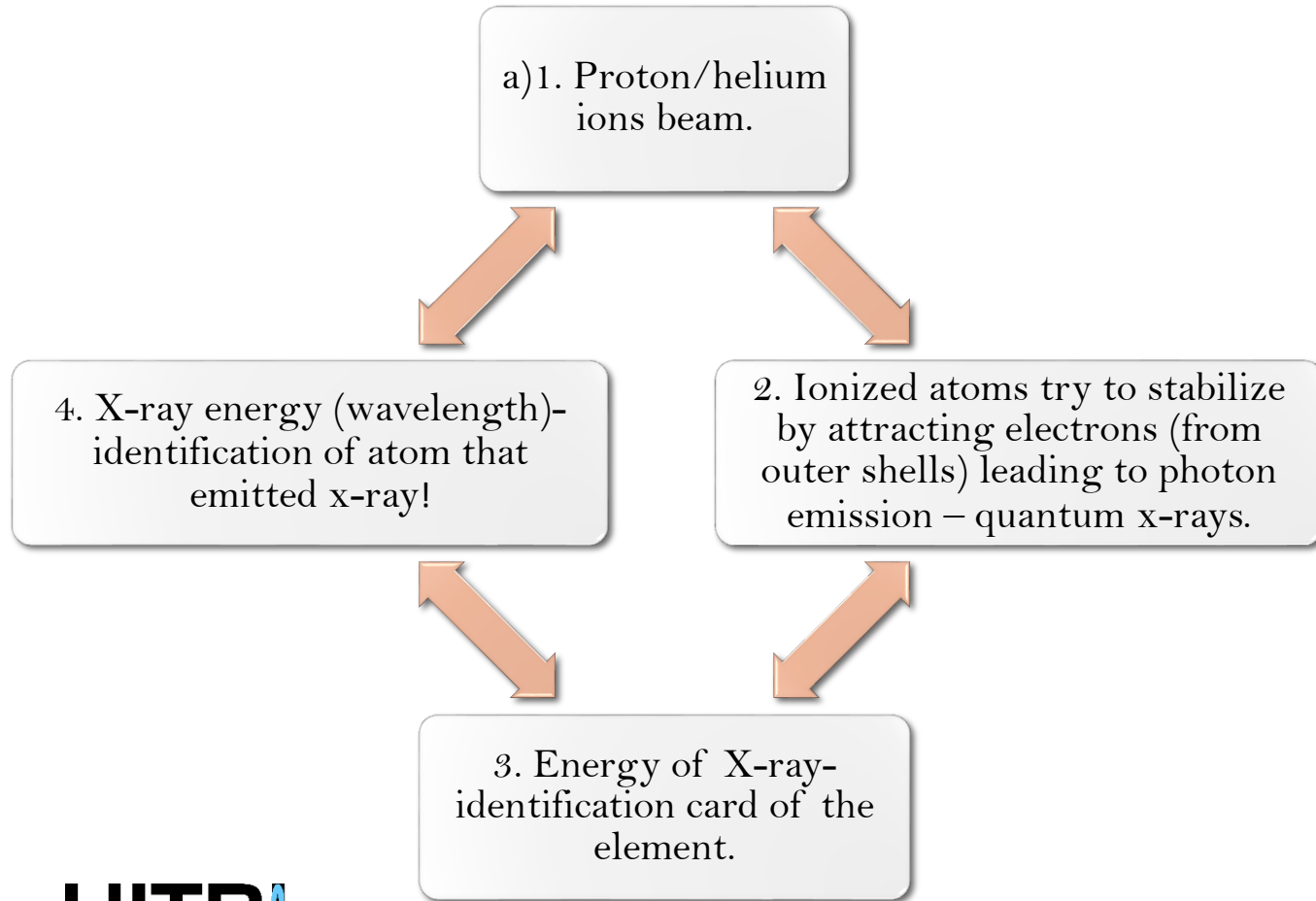


Fig 12. PIXE mechanism

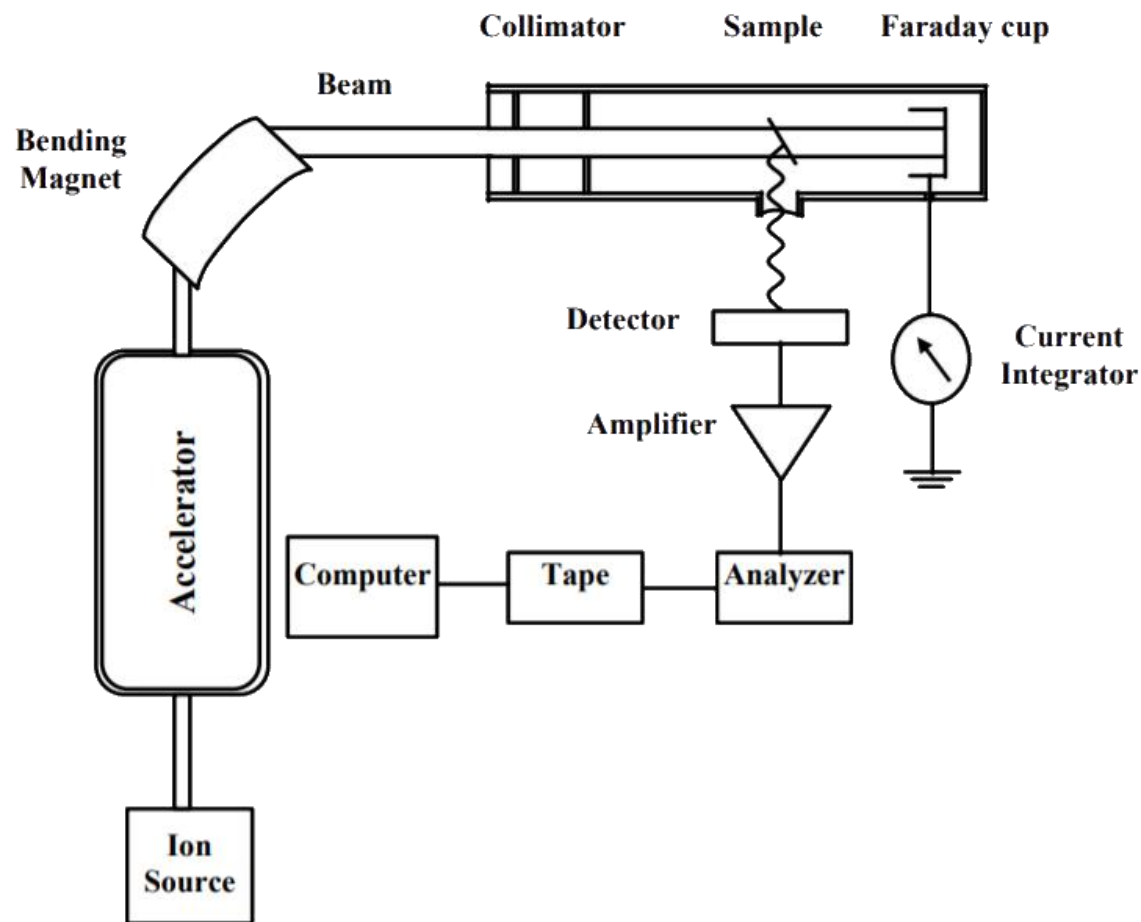


Fig. 13. Typical arrangement for the PIXE technique

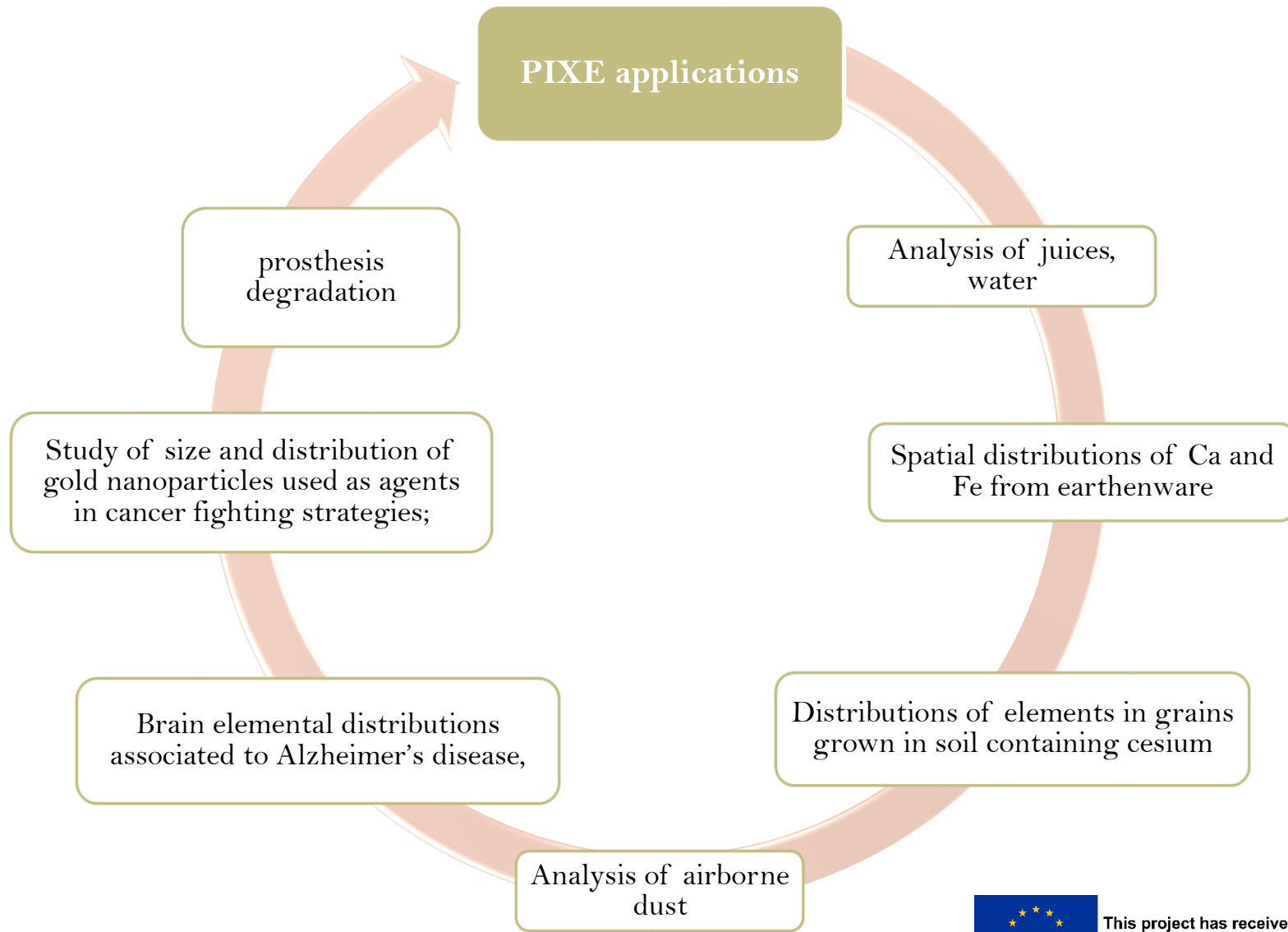
The Van de Graaff accelerator
Energies of (2-3) MeV for protons
and twice that to doubly charged
helium ions.



Several tens of μA current is
generated by the accelerator.



*(1-10) nA are currents for the PIXE
*larger currents - pile-up effect



Interesting application- μ PIXE technique

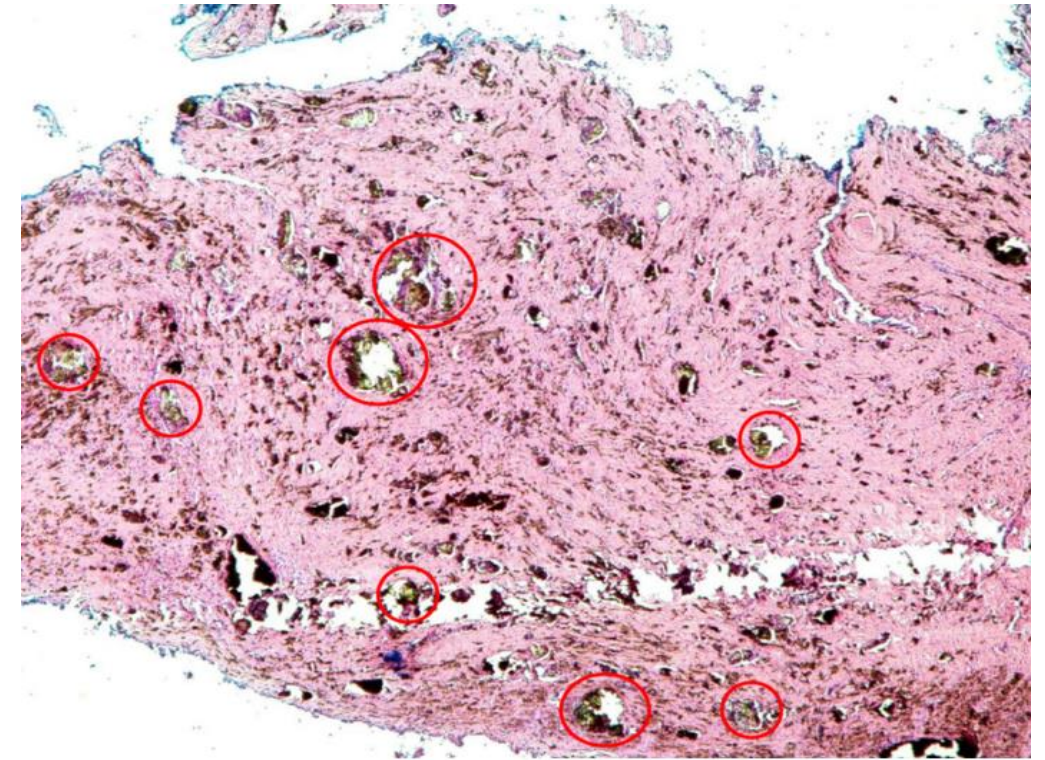
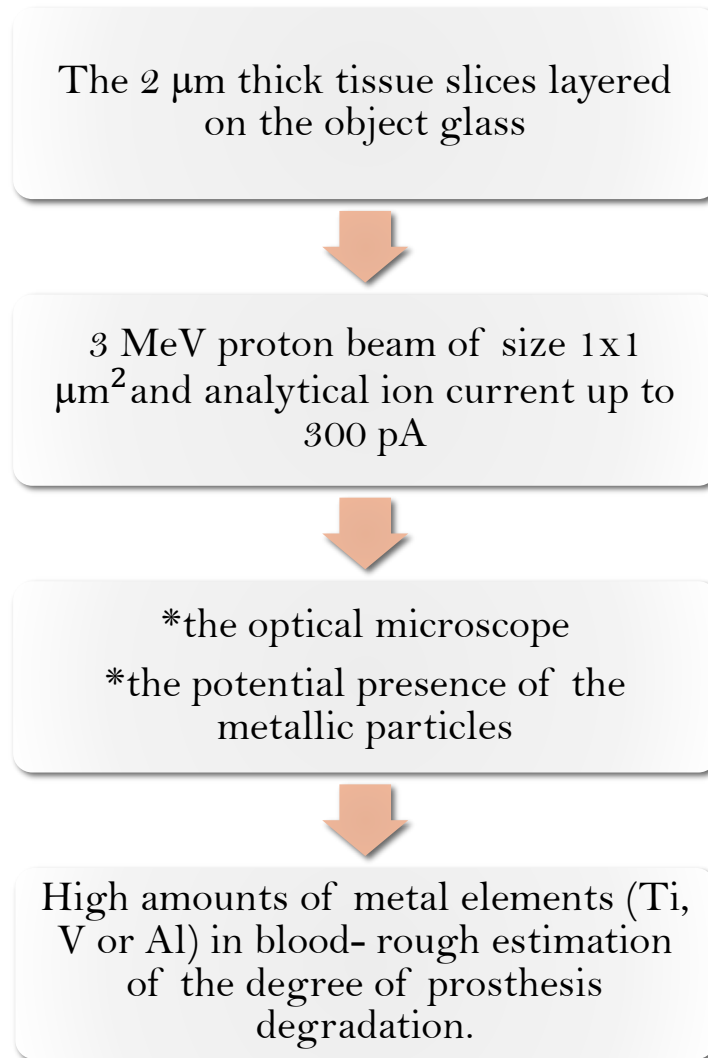


Fig. 14. Corresponds to a microphotograph taken with at 40X from a 2 μm thick slice stained for pathological examination using Hematoxylin and Eosin. The candidates to metallic particle (in yellow-green color) are marked with red circles.

Maybe we can use PIXE...

Determining the presence of radionuclides (natural and artificial origin) in the environment.



The aim is to assess the risk of exposure of the population to ionizing radiation.

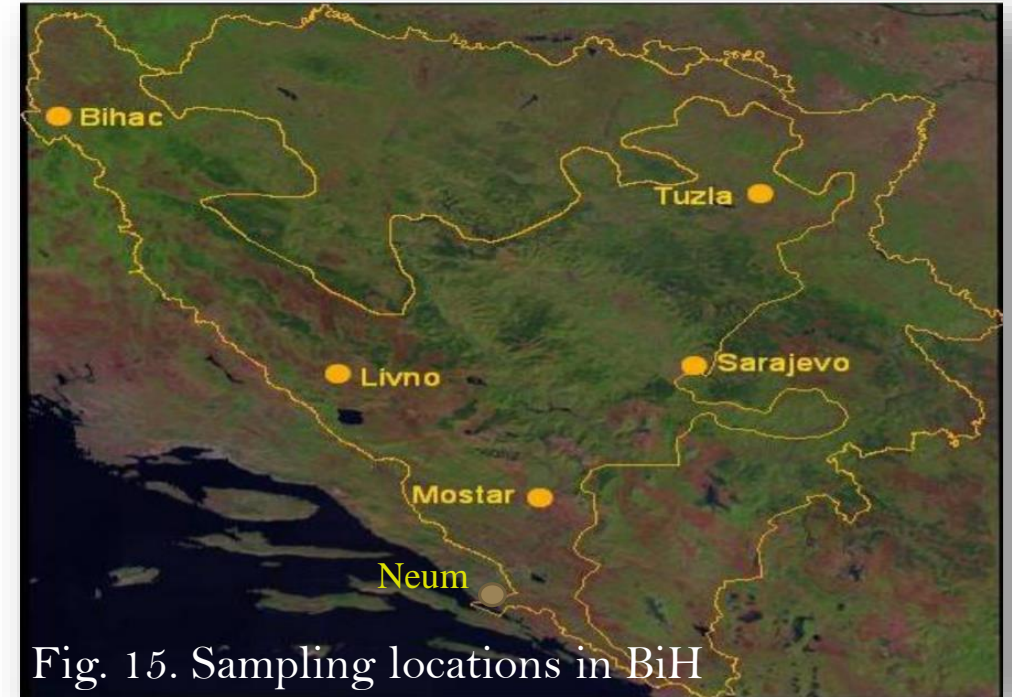
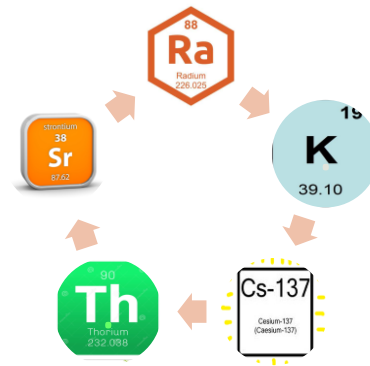


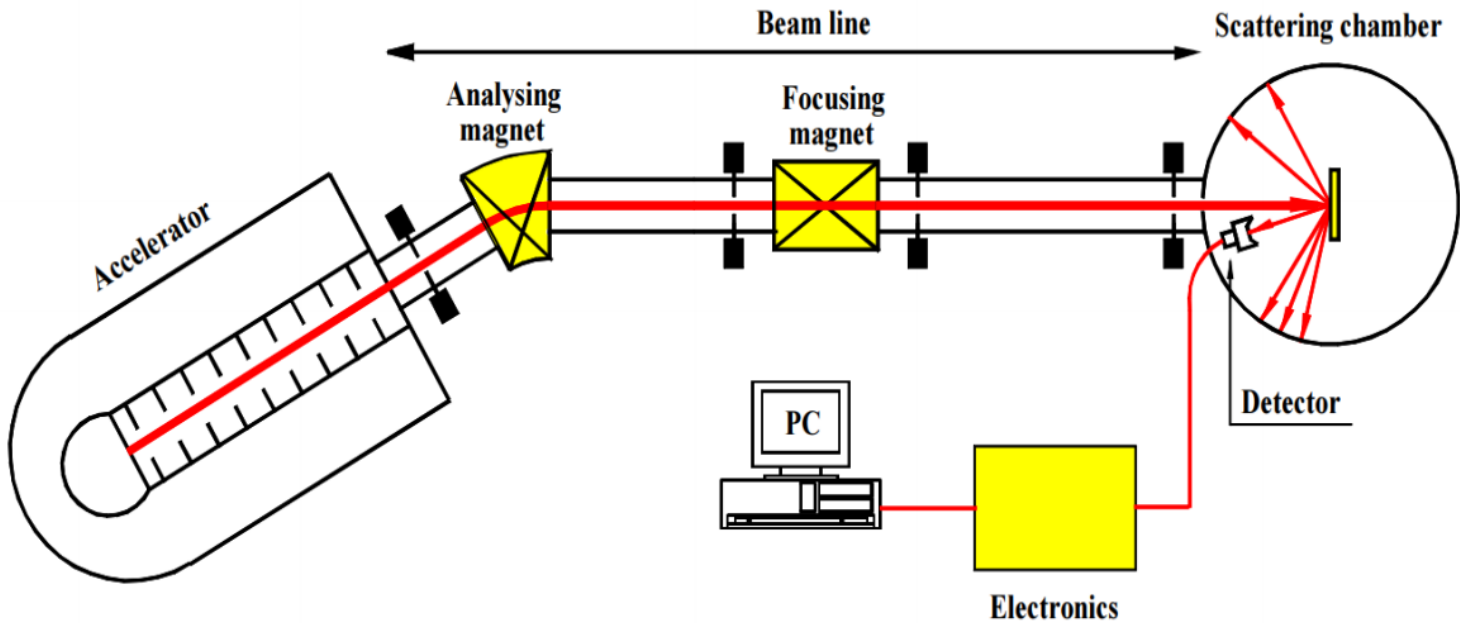
Fig. 15. Sampling locations in BiH

Natural radionuclides in food and water samples that can be detected in B&H are K^{40} , Ra^{226} and Th^{232} and artificial ones Cs^{137} and $Sr^{89/90}$.

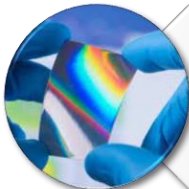
Rutherford Backscattering Spectrometry (RBS)

The RBS method- in a combination with the PIXE method.

Application of the RBS- the composition of material and profile depth of $2\ \mu\text{m}$ for α particles, and up to $20\ \mu\text{m}$ for protons.



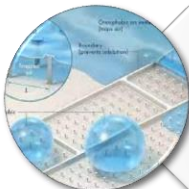
(a) metallurgy



(b) solid-state physics



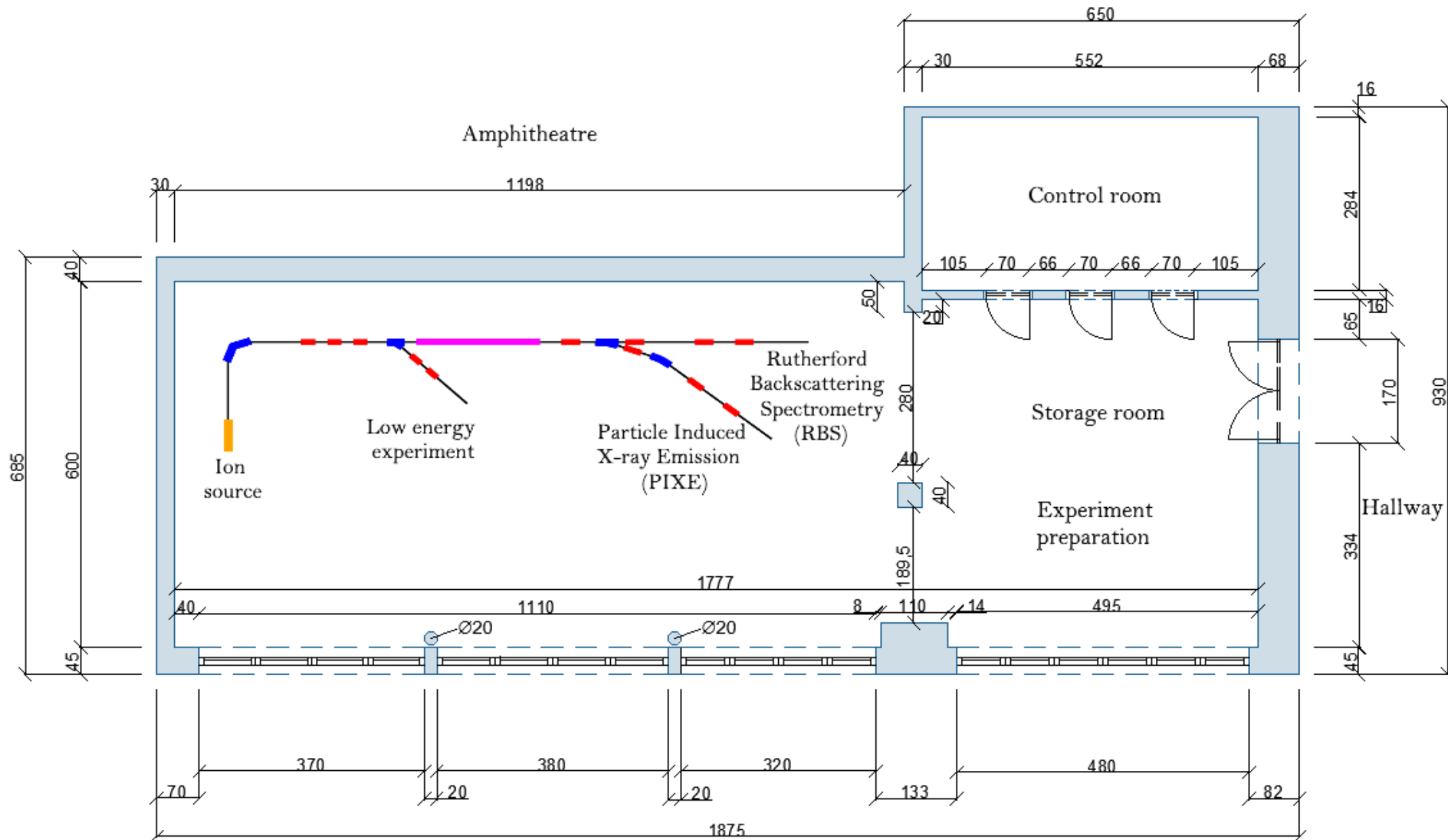
(c) electrochemistry



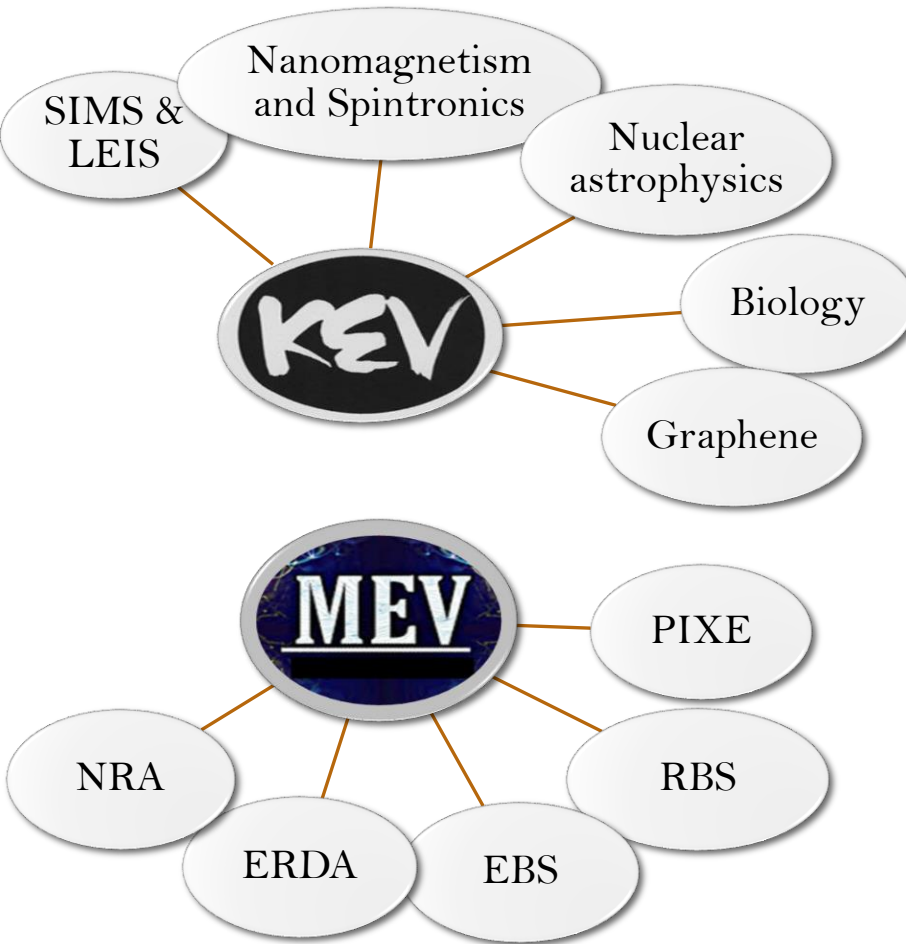
(d) surface science

Figure 16. Schematic overview of the RBS set-up

An Auto CAD drawing of a possible setup in a room located in the building of the Faculty of Science in Sarajevo



Summary



Application (keV energies)	Viability	Remarks
SIMS, LEIS	rather not	Nanogan source can produce O ⁺ , O ²⁺ and Ar ⁺ , much weaker beam currents required, other equipment, electrostatic analyzer is expensive.
Ion implantation	possible	Right intensities, additional equipment not very expensive, but low energies limit depth of implantation – requires interest from local scientists.
Graphene nanomaterials	possible	At the Chemistry department exist strong interest in this application.
Stellar physics	rather not	Other equipment (detectors) quite expensive, need strong interests from local physicists.
Biology, Agriculture, Microbiology, and Medical science.	possible	Need interests from local scientists.

Thank you!



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